

# Active IC Trim System



# M350 Wafer Trim<sup>TM</sup>

An advanced new platform for high precision, high throughput wafer-level optimization of linear and mixed-signal IC devices.







Wafer Trim™ M350

# Specifications

## System Specifications

Closed Loop X / Y / Z, Theta stage

 X/Y Resolution 0.02 um X/Y Accuracy  $\pm 2.0 \, \mu m$ 10 mm (0.39") Z Range 7 Resolution 0.13 µm Z Accuracy  $\pm 0.5 \mu m$ • Theta Range

• Theta Resolution 1.4 µrad Chuck Size Supports 100 – 200 mm wafers 50 μm (10 μm spot)

 Chuck Material | Choice of Al, Ni or Au finish

## Probing system

 Card Size 4.5 to 9" standard, 12" optional

• Probe Vision (optional)

• High and low viewing magnification of probe pins

• Probe alignment to pads  $\mid \pm 4\mu$ 

#### Beam Positioner

Type Galvanometer-based, stationary optics Positioning Accuracy < 1 µm (3 sigma) • Positioning Resolution  $< 0.06 \, \mu m$  Beam Field Size 14 mm (0.55") diameter Minimum Spot Size 6.5 – 12 µm 5 µm optional • Depth of Focus 25 µm at 6 µm spot • Laser Type Diode-pumped YAG Laser Energy 0.1 to 3 μJ @ 6.5 μm spot size, 7 ns version • Laser Energy Stability 1.0 % rms @ 1KHz

 Laser Pulse Width | 1.0 % rms @ 1KHz

Viewing

Dual CCD camera operation-separate hi-mag viewing integrated vision processing sub-system simplifies setup and improves reliability and throughput of automatic wafer alignment

### Wafer Handler (optional)

• 3-axis servo-controlled robot and pre-aligner

Capacity

(two cassettes) Control Manual or Automatic

• Wafer Support

for unattended operation 100 mm - 200 mm wafers with ability to process

Up to 50 wafers

partial wafers

 Mapping End Effector (optional):

Detects presence, absence or cross-slotted for all wafer and substrate types

 OCR and bar-code reader (optional):

SEMI character font with checksum and barcode

#### Tester (ATE-Measurement Instrumentation)

- Enhanced tester interface (ETI) and stop trim I/O integrates to industry-standard automatic test equipment (ATE)
- Integrates easily with VXI, PXI and GPIB instrumentation and custom test solutions
- Optionally available with TS910 VXI-based High Speed resistor test system

# Physical

System Unit

• Dimensions 920 mm x 864 mm x 1575 mm (30.2" x 34" x 62") · Weight 1500 lbs trimmer only Power 115 VAC, 20 A single phase, 100 – 240 VAC, 10 A (optional) 4 SCFM @ 60 psig minimum, Air clean, dry

Vacuum

 Wafer Handler Dimensions 762 mm x 864 mm x 1448 mm

• Operating Temperature | 16 – 27°C (60 – 80°F)

(30" x 34" x 57")

Internally generated

 Operating Humidity < 60 % non-condensing

#### System Compliance

- Class 1 Laser Safety
- CF Mark

## System Control

- Industrial PC
- Interfaces: Ethernet, RS232, RS485, USB
- Windows® 10 OS
- GUI based trim/test part set-up

#### The New Standard for Wafer-Based IC Optimization

The WaferTrim™ M350 laser trim system is the solution for active IC trim (trimming while probing and measuring). Built on proven technologies and principles, the M350 also features technical refinements that dramatically increase overall system throughput and enable the processing of smaller and more complex device types. In addition to active trim, the system's versatility provides link cutting, passive trim, and linear trim capabilities, allowing you to best address your process needs.

#### An Advanced & Robust Platform

All aspects of the M350 reflect the focus on providing a highly advanced platform with reliability for production. The vision, motion, laser, probe frame, and chuck assembly subsys- tems provide more accuracy and speed, with bet-ter system isolation.

#### **Enhanced Tester Interface**

The WaferTrim Series has a history of seamless integration with automated test equipment. Our Enhanced Tester Interface (ETI) responds to a library of commands that allow you to take full or partial control of the trim system through the tester. New hardware and software interface improvements provide even more flexibility and capability.

#### WaferTrim Software

The WaferTrim software runs under Windows 10 and is easier to program and use. The software provides both compatibility with your existing data/setup files and new features to increase your efficiency.

#### Worldwide Support

Throughout the semiconductor world, our applications engineers continue to develop new solutions in step with semiconductor process advancements. Our service technicians are trained in every aspect of maintenance and troubleshooting.

# Benefits

- Fully integrated state-of-the-art Laser Trimmer and Wafer Prober system
- Seamless integration to today's ATEs via Group's Enhanced Tester Interface software and real-time tester interface hardware
- Proven superior laser control ensures process consistency & highest yields
- Advanced vision and motion subsystems provide dramatically improved positioning and alignment capability
- WaferTrim<sup>™</sup> software improves efficiency

